


<b>Search Notes</b>  	<b>Application/Control No.</b>  10067460	<b>Applicant(s)/Patent Under Reexamination</b>  SEDLAK ET AL.
	<b>Examiner</b>  Nguyen-Ba, Hoang-Vu A	<b>Art Unit</b>  2421

SEARCHED			
Class	Subclass	Date	Examiner
725	87	5/8/07	HAN
725	105, 118	9/18/10	HAN
709	232-235	9/18/10	HAN

SEARCH NOTES		
Search Notes	Date	Examiner
725/\$.ccls. -- text search only	5/8/08	HAN
EAST Text Search	12/20/08	HAN
Patent Googling	12/19/08	HAN
709/232-234 -- text search only	5/22/09	HAN
709/\$.ccls. -- text search only	2/1/10	HAN
EAST Text Search -- USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	4/9/10	HAN
725/105,118; 709/232-235 -- text search	9/18/10	HAN
Interference search -- see search history printout	9/18/10	HAN
Inventor search -- no DP	9/19/10	HAN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
725	105, 118	9/18/10	HAN
709	232-235	9/18/10	HAN

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